



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20244Generic Copy

Issue Date: 24-Sep-2013**TITLE:** Final Notification of Qualification of SP Semiconductor Korea for Assembly and Test of Bipolar Power ThermalTrak™ Transistors packaged in TO-264 5L.**PROPOSED FIRST SHIP DATE:** 24-Dec-2013**AFFECTED CHANGE CATEGORY(S):** ON Semiconductor Assembly & Test**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**Contact your local ON Semiconductor Sales Office or Farrah Omar <farrah.omar@onsemi.com>**SAMPLES:** Contact your local ON Semiconductor Sales Office**ADDITIONAL RELIABILITY DATA:** AvailableContact your local ON Semiconductor Sales Office or Laura Rivers <laura.rivers@onsemi.com>**NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.**DESCRIPTION AND PURPOSE:**

ON Semiconductor announces the qualification of SP Semiconductor Korea for Assembly and Testing of Bipolar Power ThermalTrak™ Transistors packaged in TO-264 5L, previously built at PSI Manila.

SP Semiconductor facility is ISO/TS 16949:2002 certified.

**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20244****RELIABILITY DATA SUMMARY:****Reliability Test Results:****Device NJL3281DG**

Test:	Conditions:	Interval:	Results
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/160
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/160
H3TRB+PC	Ta=85C RH=85% bias=80% rated V or100V Max	1008 hrs	0/160
TC+PC	Ta= -65 C to 150 C	1000 cyc	0/160
RSH	Ta=260C, 10 sec dwell		0/20

Device NJL1302DG

Test:	Conditions:	Interval:	Results
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/240
H3TRB+PC	Ta=85C RH=85% bias=80% rated V or100V Max	1008 hrs	0/159

ELECTRICAL CHARACTERISTIC SUMMARY:

There are no changes in electrical characteristics; product performance meets data sheet specifications. Characterization data is available upon request.

CHANGED PART IDENTIFICATION:

Product from SP Semiconductor will be identified by SP site code marking.

List of affected General Parts:

NJL1302DG
NJL3281DG
NJL0281DG
NJL0302DG